







SN74LVC7001A

SCLS994A - FEBRUARY 2024 - REVISED MARCH 2024

# SN74LVC7001A Quad 2-Input AND Gates with Schmitt-Trigger Inputs

#### 1 Features

- Operating range from 1.1V to 3.6V
- 5.5V tolerant input pins
- Supports standard pinouts
- Latch-up performance exceeds 250mA per JESD 17
- ESD protection exceeds JESD 22
  - 2000V Human-Body Model (A114-A)
  - 1000V Charged-Device Model (C101)

# 2 Applications

- Combining power good signals
- Enable digital signals

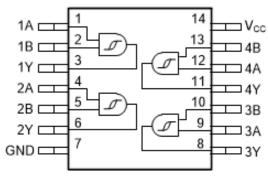
## 3 Description

The SN74LVC7001A contains four independent 2input AND gates with Schmitt-trigger inputs. Each gate performs the Boolean function Y = A • B in positive logic.

### **Package Information**

PART NUMBER PACKAGE <sup>(1)</sup>		PACKAGE SIZE(2)	BODY SIZE (NOM)(3)	
SN74LVC7001A	BQA (WQFN, 14)	3mm × 2.5mm	3mm × 2.5mm	
SIN/4EVC/001A	PW (TSSOP, 14)	5mm × 6.4mm	5mm × 4.4mm	

- For more information, see Section 11.
- The package size (length × width) is a nominal value and (2)includes pins, where applicable.
- The body size (length × width) is a nominal value and does not include pins.



**Logic Diagram** 

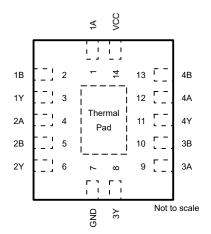


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# **4 Pin Configuration and Functions**



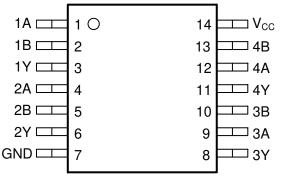


Figure 4-2. PW Package, 14 Pin TSSOP (Top View)

Figure 4-1. BQA Package, 14 Pin WQFN (Top View)

**Table 4-1. Pin Functions** 

PIN		- TYPE <sup>(1)</sup>	DESCRIPTION
NAME	NO.	IIPE	DESCRIPTION
1A	1	I	Channel 1, Input A
1B	2	ı	Channel 1, Input B
1Y	3	0	Channel 1, Output Y
2A	4	I	Channel 2, Input A
2B	5	I	Channel 2, Input B
2Y	6	0	Channel 2, Output Y
GND	7	_	Ground
3Y	8	0	Channel 3, Output Y
3A	9	I	Channel 3, Input A
3B	10	I	Channel 3, Input B
4Y	11	0	Channel 4, Output Y
4A	12	I	Channel 4, Input A
4B	13	ı	Channel 4, Input B
V <sub>CC</sub>	14	_	Positive Supply
Thermal Information <sup>(2)</sup>		_	The thermal pad can be connected to GND or left floating. Do not connect to any other signal or supply.

<sup>(1)</sup> I = input, O = output

<sup>(2)</sup> For BQA package only.



## **5 Specifications**

## 5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage range		-0.5	6.5	V
VI	Input voltage range <sup>(2)</sup>		-0.5	6.5	V
Vo	Output voltage range <sup>(2)</sup>		-0.5	V <sub>CC</sub> + 0.5	V
I <sub>IK</sub>	Input clamp current	V <sub>1</sub> < 0V		-50	mA
I <sub>OK</sub>	Output clamp current	V <sub>O</sub> < 0V		-50	mA
Io	Continuous output current			±50	mA
Io	Continuous output current throu	Continuous output current through V <sub>CC</sub> or GND		±100	mA
TJ	Junction temperature		-65	150	°C
T <sub>stg</sub>	Storage temperature		-65	150	°C

<sup>(1)</sup> Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute maximum ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If briefly operating outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not sustain damage, but it may not be fully functional. Operating the device in this manner may affect device reliability, functionality, performance, and shorten the device lifetime.

(2) The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

## 5.2 ESD Ratings

			VALUE	UNIT
V <sub>(ESD)</sub> Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 <sup>(1)</sup>	±2000	\/	
	discharge	Charged-device model (CDM), per ANSI/ESDA/JEDEC JS-002 <sup>(2)</sup>	±1000	v

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

### 5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

Specifications	Description	Condition	MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage		1.1	3.6	V
VI	Input voltage			5.5	V
Vo	Output voltage	(High or low state)		V <sub>CC</sub>	V
		V <sub>CC</sub> = 1.8V		-4	
	High lovel output ourrent	V <sub>CC</sub> = 2.3V		-8	mA
I <sub>OH</sub> High-level output current	V <sub>CC</sub> = 2.7V		-12	IIIA	
		V <sub>CC</sub> = 3V		-24	
		V <sub>CC</sub> = 1.8V		4	
	L L L	V <sub>CC</sub> = 2.3V		8	mA
IOL	Low-level output current	V <sub>CC</sub> = 2.7V		12	IIIA
		V <sub>CC</sub> = 3V		24	
Δt/Δν	Input transition rise or fall rate			10	ns/V
T <sub>A</sub>	Operating free-air temperature		-40	125	°C



## **5.4 Thermal Information**

THERMAL METRIC(1)		Package	Package Options			
		PW (TSSOP)	BQA (WQFN)	UNIT		
		14 PINS	14 PINS			
R <sub>0JA</sub>	Junction-to-ambient thermal resistance	150.8	102.3	°C/W		
R <sub>0JC(top)</sub>	Junction-to-case (top) thermal resistance	78.3	96.8	°C/W		
$R_{\theta JB}$	Junction-to-board thermal resistance	93.8	70.9	°C/W		
$\Psi_{JT}$	Junction-to-top characterization parameter	24.7	16.6	°C/W		
$Y_{JB}$	Junction-to-board characterization parameter	93.2	70.9	°C/W		
R <sub>0JC(bot)</sub>	Junction-to-case (bottom) thermal resistance	-	50.1	°C/W		

<sup>(1)</sup> For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

## **5.5 Electrical Characteristics**

over operating free-air temperature range (unless otherwise noted)

	TEST CONDITIONS	V	-40°C to	-40°C to 125°C		
PARAMETER	TEST CONDITIONS	V <sub>cc</sub>	MIN	TYP	MAX	UNIT
V <sub>T+</sub>	Positive-going input threshold voltage	1.1V	0.5		0.8	V
V <sub>T+</sub>	Positive-going input threshold voltage	1.5V	0.7		1.11	V
V <sub>T+</sub>	Positive-going input threshold voltage	1.65V	0.4		1.3	V
V <sub>T+</sub>	Positive-going input threshold voltage	1.95V	0.6		1.5	V
V <sub>T+</sub>	Positive-going input threshold voltage	2.3V	0.8		1.7	V
V <sub>T+</sub>	Positive-going input threshold voltage	2.5V	0.8		1.7	V
V <sub>T+</sub>	Positive-going input threshold voltage	2.7V	0.8		2	V
V <sub>T+</sub>	Positive-going input threshold voltage	3V	0.9		2	V
V <sub>T+</sub>	Positive-going input threshold voltage	3.6V	1.1		2	V
V <sub>T-</sub>	Negative-going input threshold voltage	1.1V	0.2		0.6	V
V <sub>T-</sub>	Negative-going input threshold voltage	1.5V	0.34		0.75	V
V <sub>T-</sub>	Negative-going input threshold voltage	1.65V	0.2		0.9	V
V <sub>T-</sub>	Negative-going input threshold voltage	1.95V	0.3		1	V
V <sub>T-</sub>	Negative-going input threshold voltage	2.3V	0.4		1.2	V
V <sub>T-</sub>	Negative-going input threshold voltage	2.5V	0.4		1.2	V
V <sub>T-</sub>	Negative-going input threshold voltage	2.7V	0.4		1.4	V
V <sub>T-</sub>	Negative-going input threshold voltage	3V	0.6		1.5	V
V <sub>T-</sub>	Negative-going input threshold voltage	3.6V	0.8		1.7	V
$\Delta V_{T}$	Hysteresis (V <sub>T+</sub> - V <sub>T-</sub> )	1.1V	0.07		0.53	V
$\Delta V_{T}$	Hysteresis (V <sub>T+</sub> - V <sub>T-</sub> )	1.5V	0.18		0.60	V
$\Delta V_{T}$	Hysteresis (V <sub>T+</sub> - V <sub>T-</sub> )	1.65V	0.1		1.2	V
$\Delta V_{T}$	Hysteresis (V <sub>T+</sub> - V <sub>T-</sub> )	1.95V	0.2		1.3	V
$\Delta V_{T}$	Hysteresis (V <sub>T+</sub> - V <sub>T-</sub> )	2.3V	0.3		1.3	V
$\Delta V_{T}$	Hysteresis (V <sub>T+</sub> - V <sub>T-</sub> )	2.5V	0.3		1.3	V
$\Delta V_{T}$	Hysteresis (V <sub>T+</sub> - V <sub>T-</sub> )	2.7V	0.3		1.1	V
$\Delta V_{T}$	Hysteresis (V <sub>T+</sub> - V <sub>T-</sub> )	3V	0.3		1.2	V
$\Delta V_{T}$	Hysteresis (V <sub>T+</sub> - V <sub>T-</sub> )	3.6V	0.3		1.2	V
V <sub>OH</sub>	I <sub>OH</sub> = -100μA	1.1V to 3.6V	V <sub>CC</sub> - 0.2			V
V <sub>OH</sub>	I <sub>OH</sub> = -4mA	1.65V	1.2			V
V <sub>OH</sub>	I <sub>OH</sub> = -8mA	2.3V	1.75			V



## **5.5 Electrical Characteristics (continued)**

over operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS	V	-40°C to	-40°C to 125°C		
PARAMETER	TEST CONDITIONS	V <sub>cc</sub>	MIN	TYP	MAX	UNIT
V <sub>OH</sub>	I = 12mA	2.7V	2.2			V
V <sub>OH</sub>	I <sub>OH</sub> = −12mA	3V	2.4			V
V <sub>OH</sub>	I <sub>OH</sub> = –24mA	3V	2.2			V
V <sub>OL</sub>	I <sub>OH</sub> = 100μA	1.1V to 3.6V			0.15	V
V <sub>OL</sub>	I <sub>OH</sub> = 4mA	1.65V			0.45	V
V <sub>OL</sub>	I <sub>OH</sub> = 8mA	2.3V			0.7	V
V <sub>OL</sub>	I <sub>OH</sub> = 12mA	2.7V			0.4	V
V <sub>OL</sub>	I <sub>OH</sub> = 24mA	3V			0.55	V
I <sub>1</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND	3.6V			±5	μA
I <sub>off</sub>	V <sub>I</sub> or V <sub>O</sub> = V <sub>CC</sub>	0V		-	±10	μA
I <sub>cc</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND, I <sub>O</sub> = 0	3.6V		-	40	μA
ΔI <sub>CC</sub>	One input at $V_{CC}$ - 0.6V, other inputs at $V_{CC}$ or GND	2.7V to 3.6V			500	μA
C <sub>I</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND	3.3V		-		pF
Co	V <sub>O</sub> = V <sub>CC</sub> or GND	3.3V				pF
C <sub>PD</sub>	f = 10MHz	1.8V		31		pF
C <sub>PD</sub>	f = 10MHz	2.5V		31		pF
C <sub>PD</sub>	f = 10MHz	3.3V		32		pF

## 5.6 Switching Characteristics

over operating free-air temperature range; typical values measured at  $T_A = 25$ °C (unless otherwise noted). See *Parameter Measurement Information* 

PARAMETER	PROM TO (OUTPUT) LOAD CARACITANICE		V	-40°C to 125°C			UNIT	
PARAMETER	(INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	V <sub>cc</sub>	MIN	TYP	MAX	UNII
t <sub>pd</sub>	A or B	Υ	C <sub>L</sub> = 15pF	1.2V ± 0.1V		12	44	ns
t <sub>pd</sub>	A or B	Υ	C <sub>L</sub> = 15pF	1.5V ± 0.12V		9	15	ns
t <sub>pd</sub>	A or B	Υ	C <sub>L</sub> = 30pF	1.8V ± 0.15V			10.2	ns
t <sub>pd</sub>	A or B	Υ	C <sub>L</sub> = 30pF	2.5V ± 0.2V			6.9	ns
t <sub>pd</sub>	A or B	Υ	C <sub>L</sub> = 50pF	2.7V			6.4	ns
t <sub>pd</sub>	A or B	Υ	C <sub>L</sub> = 50pF	3.3V ± 0.3V			5.6	ns
t <sub>sk(o)</sub>				3.3V ± 0.3V			1.5	ns

## **5.7 Noise Characteristics**

VCC = 3.3V, CL = 50pF, TA = 25°C

PARAMETER	DESCRIPTION	MIN	TYP	MAX	UNIT
V <sub>OL(P)</sub>	Quiet output, maximum dynamic V <sub>OL</sub>		0.9	0.8	V
V <sub>OL(V)</sub>	Quiet output, minimum dynamic V <sub>OL</sub>	-0.8	-0.3		V
V <sub>OH(V)</sub>	Quiet output, minimum dynamic V <sub>OH</sub>	2.2	3.3		V
V <sub>IH(D)</sub>	High-level dynamic input voltage	2.0			V
V <sub>IL(D)</sub>	Low-level dynamic input voltage			0.8	V

## **5.8 Typical Characteristics**

T<sub>A</sub> = 25°C (unless otherwise noted)

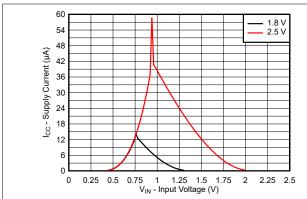


Figure 5-1. Supply Current Across Input Voltage 1.8V and 2.5V Supply

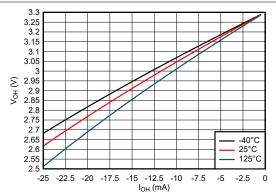


Figure 5-2. Output Voltage vs Current in HIGH State; 3.3V Supply

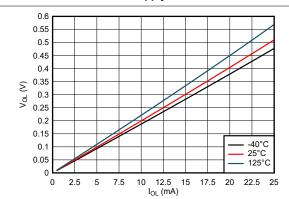


Figure 5-3. Output Voltage vs Current in LOW State; 3.3V Supply

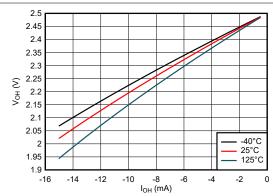
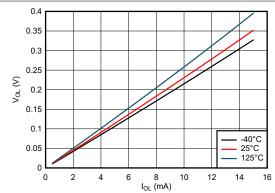
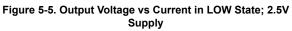


Figure 5-4. Output Voltage vs Current in HIGH State; 2.5V Supply





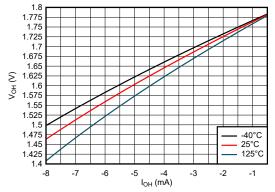
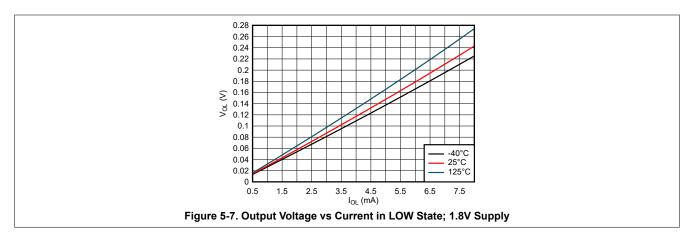


Figure 5-6. Output Voltage vs Current in HIGH State; 1.8V Supply



# **5.8 Typical Characteristics (continued)**

T<sub>A</sub> = 25°C (unless otherwise noted)



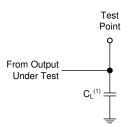


### **6 Parameter Measurement Information**

Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics:  $PRR \le 1MHz$ ,  $Z_O = 50\Omega$ .

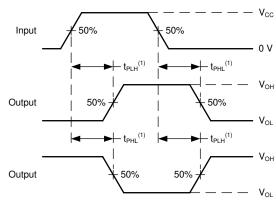
For clock inputs,  $f_{\text{max}}$  is measured when the input duty cycle is 50%.

The outputs are measured one at a time with one input transition per measurement.



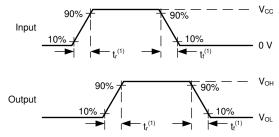
(1) C<sub>L</sub> includes probe and test-fixture capacitance.

Figure 6-1. Load Circuit for Push-Pull Outputs



(1) The greater between  $t_{\text{PLH}}$  and  $t_{\text{PHL}}$  is the same as  $t_{\text{pd}}.$ 

Figure 6-2. Voltage Waveforms Propagation Delays



(1) The greater between  $t_{r}$  and  $t_{f}$  is the same as  $t_{t}$ .

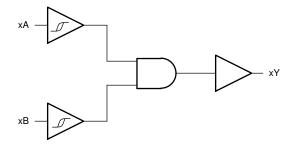
Figure 6-3. Voltage Waveforms, Input and Output Transition Times

## 7 Detailed Description

#### 7.1 Overview

This device contains four independent 2-input AND gates with Schmitt-trigger inputs. Each gate performs the Boolean function  $Y = A \bullet B$  in positive logic.

### 7.2 Functional Block Diagram



## 7.3 Feature Description

## 7.3.1 Balanced CMOS Push-Pull Outputs

A balanced output allows the device to sink and source similar currents. The drive capability of this device may create fast edges into light loads so routing and load conditions should be considered to prevent ringing. Additionally, the outputs of this device are capable of driving larger currents than the device can sustain without being damaged. It is important for the output power of the device to be limited to avoid damage due to over-current. The electrical and thermal limits defined in the Absolute Maximum Ratings must be followed at all times.

The SN74LVC7001A can drive a load with a total capacitance less than or equal to the maximum load listed in the Switching Characteristics connected to a high-impedance CMOS input while still meeting all of the datasheet specifications. Larger capacitive loads can be applied, however it is not recommended to exceed the provided load value. If larger capacitive loads are required, it is recommended to add a series resistor between the output and the capacitor to limit output current to the values given in the Absolute Maximum Ratings.

#### 7.3.2 CMOS Schmitt-Trigger Inputs

Standard CMOS inputs are high impedance and are typically modeled as a resistor from the input to ground in parallel with the input capacitance given in the *Electrical Characteristics*. The worst case resistance is calculated with the maximum input voltage, given in the Absolute Maximum Ratings, and the maximum input leakage current, given in the *Electrical Characteristics*, using ohm's law (R = V ÷ I).

The Schmitt-trigger input architecture provides hysteresis as defined by ΔV<sub>T</sub> in the *Electrical Characteristics*, which makes this device extremely tolerant to slow or noisy inputs. While the inputs can be driven much slower than standard CMOS inputs, it is still recommended to properly terminate unused inputs. Driving the inputs slowly will also increase dynamic current consumption of the device. For additional information regarding Schmitt-trigger inputs, please see Understanding Schmitt Triggers.

### 7.3.3 Clamp Diode Structure

Figure 7-1 shows the inputs and outputs to this device have negative clamping diodes only.

### **CAUTION**

Voltages beyond the values specified in the Absolute Maximum Ratings table can cause damage to the device. The input and output voltage ratings may be exceeded if the input and output clampcurrent ratings are observed.



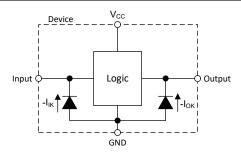


Figure 7-1. Electrical Placement of Clamping Diodes for Each Input and Output

## 7.4 Device Functional Modes

**Table 7-1. Function Table** 

INP	UTS	OUTPUT
Α	В	Y
Н	Н	Н
L	X	L
Х	L	L

## 8 Application and Implementation

#### Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

### 8.1 Application Information

In this application, three 2-input AND gates are combined to produce a 4-input AND gate function as shown in Figure 8-1. The fourth gate can be used for another application in the system, or the inputs can be grounded and the channel left unused.

This device is used to directly control the RESET pin of a motor controller. The controller requires four input signals to all be HIGH before being enabled, and should be disabled in the event that any one signal goes LOW. The 4-input AND gate function combines the four individual reset signals into a single active-low reset signal.

## 8.2 Typical Application

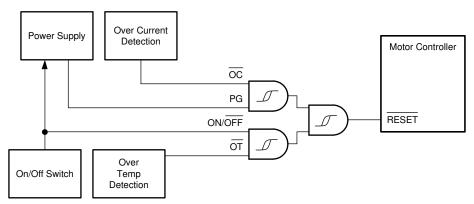


Figure 8-1. Typical Application Schematic

#### 8.2.1 Design Requirements

#### 8.2.1.1 Power Considerations

Ensure the desired supply voltage is within the range specified in the Recommended Operating Conditions. The supply voltage sets the device's electrical characteristics as described in the *Electrical Characteristics*.

The supply must be capable of sourcing current equal to the total current to be sourced by all outputs of the SN74LVC7001A plus the maximum supply current, I<sub>CC</sub>, listed in the *Electrical Characteristics*. The logic device can only source or sink as much current as it is provided at the supply and ground pins, respectively. Be sure not to exceed the maximum total current through GND or  $V_{CC}$  listed in the Absolute Maximum Ratings.

Total power consumption can be calculated using the information provided in CMOS Power Consumption and C<sub>pd</sub> Calculation.

Thermal increase can be calculated using the information provided in Thermal Characteristics of Standard Linear and Logic (SLL) Packages and Devices.

#### CAUTION

The maximum junction temperature, T<sub>J</sub>(max) listed in the Absolute Maximum Ratings, is an additional limitation to prevent damage to the device. Do not violate any values listed in the Absolute Maximum Ratings. These limits are provided to prevent damage to the device.

### 8.2.1.2 Input Considerations

Input signals must cross  $V_{t-}(min)$  to be considered a logic LOW, and  $V_{t+}(max)$  to be considered a logic HIGH. Do not exceed the maximum input voltage range found in the *Absolute Maximum Ratings* .

Unused inputs must be terminated to either  $V_{CC}$  or ground. These can be directly terminated if the input is completely unused, or they can be connected with a pull-up or pull-down resistor if the input is to be used sometimes, but not always. A pull-up resistor is used for a default state of HIGH, and a pull-down resistor is used for a default state of LOW. The resistor size is limited by drive current of the controller, leakage current into the SN74LVC7001A, as specified in the *Electrical Characteristics*, and the desired input transition rate. A  $10k\Omega$  resistor value is often used due to these factors.

The SN74LVC7001A has no input signal transition rate requirements because it has Schmitt-trigger inputs.

Another benefit to having Schmitt-trigger inputs is the ability to reject noise. Noise with a large enough amplitude can still cause issues. To know how much noise is too much, please refer to the  $\Delta V_T$ (min) in the *Electrical Characteristics*. This hysteresis value will provide the peak-to-peak limit.

Unlike what happens with standard CMOS inputs, Schmitt-trigger inputs can be held at any valid value without causing huge increases in power consumption. The typical additional current caused by holding an input at a value other than V<sub>CC</sub> or ground is plotted in the *Typical Characteristics*.

Refer to Section 7.3 for additional information regarding the inputs for this device.

#### 8.2.1.3 Output Considerations

The positive supply voltage is used to produce the output HIGH voltage. Drawing current from the output will decrease the output voltage as specified by the  $V_{OH}$  specification in the *Electrical Characteristics*. Similarly, the ground voltage is used to produce the output LOW voltage. Sinking current into the output will increase the output voltage as specified by the  $V_{OL}$  specification in the *Electrical Characteristics*.

Unused outputs can be left floating. Do not connect outputs directly to V<sub>CC</sub> or ground.

Refer to Section 7.3 for additional information regarding the outputs for this device.

### 8.2.2 Detailed Design Procedure

- Add a decoupling capacitor from V<sub>CC</sub> to GND. The capacitor needs to be placed physically close to the device and electrically close to both the V<sub>CC</sub> and GND pins. An example layout is shown in the Section 8.4.
- Ensure the capacitive load at the output is ≤ 70pF. This is not a hard limit; however, it will
  optimize performance. This can be accomplished by providing short, appropriately sized traces from the
  SN74LVC7001A to the receiving device.
- 3. Ensure the resistive load at the output is larger than (V<sub>CC</sub> / I<sub>O</sub>(max)) Ω. This will not violate the maximum output current from the *Absolute Maximum Ratings*. Most CMOS inputs have a resistive load measured in megaohms; much larger than the minimum calculated above.
- 4. Thermal issues are rarely a concern for logic gates, however the power consumption and thermal increase can be calculated using the steps provided in the application report, CMOS Power Consumption and Cpd Calculation

#### 8.2.3 Application Curves

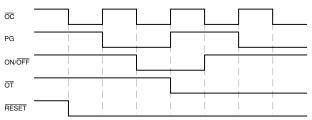


Figure 8-2. Typical Application Timing Diagram

### 8.3 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each  $V_{CC}$  terminal should have a bypass capacitor to prevent power disturbance. A  $0.1\mu F$  capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The  $0.1\mu F$  and  $1\mu F$  capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results, as shown in *Figure 8-3*.

## 8.4 Layout

### 8.4.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must never be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or  $V_{CC}$ , whichever makes more sense for the logic function or is more convenient.

#### 8.4.2 Layout Example

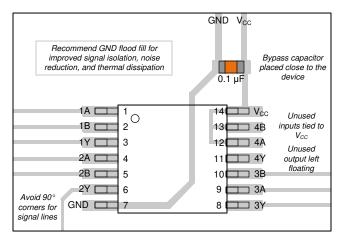


Figure 8-3. Example Layout for the SN74LVC7001A



## 9 Device and Documentation Support

## 9.1 Documentation Support

#### 9.1.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, Introduction to Logic application report
- Texas Instruments, Implications of Slow or Floating CMOS Inputs application note

## 9.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

### 9.3 Support Resources

TI E2E™ support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

#### 9.4 Trademarks

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## 9.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 9.6 Glossary

TI Glossarv

This glossary lists and explains terms, acronyms, and definitions.

### 10 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

#### Changes from Revision \* (February 2024) to Revision A (March 2024)

Page

Changed the status of the PW package from: preview to: active ......1

### 11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser based versions of this data sheet, refer to the left hand navigation.



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#### PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
SN74LVC7001ABQAR	ACTIVE	WQFN	BQA	14	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LC701A	Samples
SN74LVC7001APWR	ACTIVE	TSSOP	PW	14	3000	RoHS & Green	NIPDAU   SN	Level-1-260C-UNLIM	-40 to 125	LVC7001	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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# **PACKAGE OPTION ADDENDUM**

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#### OTHER QUALIFIED VERSIONS OF SN74LVC7001A:

Automotive: SN74LVC7001A-Q1

NOTE: Qualified Version Definitions:

• Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

# **PACKAGE MATERIALS INFORMATION**

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## TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74LVC7001ABQAR	WQFN	BQA	14	3000	180.0	12.4	2.8	3.3	1.1	4.0	12.0	Q1
SN74LVC7001APWR	TSSOP	PW	14	3000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74LVC7001APWR	TSSOP	PW	14	3000	330.0	12.4	6.85	5.45	1.6	8.0	12.0	Q1

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## \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74LVC7001ABQAR	WQFN	BQA	14	3000	210.0	185.0	35.0
SN74LVC7001APWR	TSSOP	PW	14	3000	353.0	353.0	32.0
SN74LVC7001APWR	TSSOP	PW	14	3000	366.0	364.0	50.0

2.5 x 3, 0.5 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



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PLASTIC QUAD FLAT PACK-NO LEAD



### NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.



PLASTIC QUAD FLAT PACK-NO LEAD



NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC QUAD FLAT PACK-NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

PW (R-PDSO-G14)

## PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
- B. This drawing is subject to change without notice.
  - Sody length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
- E. Falls within JEDEC MO-153



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